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<th><strong>Title</strong></th>
<th>Motion detection, the Wigner distribution function, and the optical fractional Fourier transform</th>
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<tr>
<td><strong>Authors(s)</strong></td>
<td>Sheridan, John T.; Hennelly, Bryan M.; Kelly, Damien P.</td>
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<tr>
<td><strong>Publication date</strong></td>
<td>2003-06-01</td>
</tr>
<tr>
<td><strong>Publication information</strong></td>
<td>Optics Letters, 28 (11): 884-886</td>
</tr>
<tr>
<td><strong>Publisher</strong></td>
<td>Optical Society of America</td>
</tr>
<tr>
<td><strong>Link to online version</strong></td>
<td><a href="http://dx.doi.org/10.1364/OL.28.000884">http://dx.doi.org/10.1364/OL.28.000884</a></td>
</tr>
<tr>
<td><strong>Item record/more information</strong></td>
<td><a href="http://hdl.handle.net/10197/3473">http://hdl.handle.net/10197/3473</a></td>
</tr>
<tr>
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<tr>
<td><strong>Publisher's version (DOI)</strong></td>
<td>10.1364/OL.28.000884</td>
</tr>
</tbody>
</table>

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Motion detection, the Wigner distribution function, and the optical fractional Fourier transform

John T. Sheridan, Bryan Hennelly, and Damien Kelly

Department of Electronic and Electrical Engineering, Faculty of Engineering and Architecture, University College Dublin, Belfield, Dublin 4, Republic of Ireland

Received December 13, 2002

It is shown that both surface tilting and translational motion can be independently estimated by use of the speckle photographic technique by capturing consecutive images in two different fractional Fourier domains. A geometric interpretation, based on use of the Wigner distribution function, is presented to describe this application of the optical fractional Fourier transform when little prior information is known about the motion.

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OCIS codes: 070.0070, 120.6150.

Speckle photography is a practical means of extracting in-plane translation and tilting motion information by use of captured intensity information.\textsuperscript{1,2} Tilt measurement, for example, involves the capture of the optical Fourier transform of the reflected surface field. Adding or subtracting two sequential images and numerically calculating the Fourier transform (FT) of the result produces a set of interference fringes whose period is inversely proportional to any constant shift in field spatial frequency and so in surface tilt.

In this case no information is known about surface translation. Angular velocity and acceleration can be found based on a series of sequentially captured images. The resolution and the dynamical range of detectable movements are fixed and depend on the wavelength used, the reflected field speckle size (including decorrelation effects), and the measurement system used, e.g., the system’s point-spread function and the CCD’s pixel size and sensitivity. The time resolution depends on the speed of the camera used.

The fractional Fourier transform (FRT), which is a generalization of the FT, has received a great deal of attention in the optics literature.\textsuperscript{2–7} The combination of the holographic interferometric principle and an optical implementation of the FRT was shown previously to permit simultaneous tilt and in-plane translation detection.\textsuperscript{8} It was also shown that using an optical FRT system permits speckle photography to be extended to allow for simultaneous measurement of tilted and in-plane translational motion.\textsuperscript{9} Furthermore, it has been experimentally demonstrated\textsuperscript{10} that the extra degree of freedom made available by the use of an optical implementation of the FRT permits controlled variation of the minimum resolution and dynamical range of measurement of tilting (rotational) motion. The experimental results were achieved with an optical FRT system called a fake-zoom lens.\textsuperscript{11} Varying the distances between the lenses permits the generation of several fractional order planes with constant magnification (scale factor).

The Wigner distribution function\textsuperscript{12,13} (WDF) has been shown to be of practical value for the understand-
In the FRT domain we can describe the motion by using the normalized parameter definition of the FRT of angle $\theta$.

Initially the field in this FRT domain is given by

$$F_\theta[u(x)](q) = \frac{1}{(2\pi|\sin \theta|)^{1/2}} \exp\left(-j \frac{\pi}{2} \left[ \frac{1}{2} + J\left(\frac{\theta}{\pi}\right) \right] \right)$$

$$U(k) = F[u(x)] \rightarrow U(k - \kappa) \exp(+j\kappa k),$$

whereas, as already indicated, in phase space we can write that

$$W(x, k) \rightarrow W(x - \xi, k - \kappa).$$

In the FRT domain we can describe the motion by using the normalized parameter definition of the FRT of angle $\theta$. Initially the field in this FRT domain is given by

$$F_\theta[u(x) - \xi \exp(+j\kappa x)](q) = \frac{1}{(2\pi|\sin \theta|)^{1/2}} \exp\left(-j \frac{\pi}{2} \left[ \frac{1}{2} + J\left(\frac{\theta}{\pi}\right) \right] \right)$$

$$\times \exp\left[ -j \frac{\pi}{2} \left[ \frac{1}{2} + J\left(\frac{\theta}{\pi}\right) \right] \right]$$

$$+ \frac{j}{2} q^2 \cot \theta \int_{-\infty}^{\infty} u(x) \exp\left[ \frac{j}{2} x^2 \cot \theta - jqx \cot \theta \right] dx.$$

Following motion, the projection on the fractional Fourier axis is given by

$$F_\theta[u(x - \xi) \exp(j\kappa x)](q) = \frac{1}{(2\pi|\sin \theta|)^{1/2}} \exp\left(-j \frac{\pi}{2} \left[ \frac{1}{2} + J\left(\frac{\theta}{\pi}\right) \right] \right)$$

$$\times \exp\left[ -j \frac{\pi}{2} \left[ \frac{1}{2} + J\left(\frac{\theta}{\pi}\right) \right] \right]$$

$$+ \frac{j}{2} \cot \theta \left[ q^2 + \xi^2 - 2 \frac{q\xi}{\cos \theta} + 2\kappa \xi \tan \theta \right]$$

$$\times \int_{-\infty}^{\infty} u(y) \exp\left[ \frac{j}{2} y^2 \cot \theta - j(q - Q)y \cot \theta \right] dy,$$

where we have used the substitution $y = x - \xi$.

Comparing Eqs. (3) and (4), we can see that the FRT of the original field, $U_\theta(q)$, has been multiplied by a phase factor and been shifted by an amount $Q = \xi \cos \theta + \kappa \sin \theta$. From Fig. 1 we identify this shift distance in $q$ as the projection onto $q$ of the actual shift distance $\sqrt{\xi^2 + \kappa^2}$. We can now write in addition to Eqs. (2) that

$$U_\theta(q) \rightarrow U(q - Q) \exp[j\Phi(q)],$$

where

$$\Phi(q) = q \cot \theta (Q - \frac{\xi}{\cos \theta}) + \cot \frac{\theta}{2} (\xi^2 - Q^2) + \kappa \xi.$$

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$$\Phi(q) = q \cot \theta (Q - \frac{\xi}{\cos \theta}) + \cot \frac{\theta}{2} (\xi^2 - Q^2) + \kappa \xi.$$
If we assume that $\Delta \theta$ is small, carrying out Taylor series expansions will yield

$$\xi = -\frac{\Delta Q}{\Delta \theta} \sin(\theta) + Q \cos(\theta)$$

$$-\frac{\Delta \theta}{6} (3Q + \Delta Q) \sin(\theta) + O(\Delta \theta)^3$$

$$\approx -\frac{dQ}{d\theta} \sin(\theta) + Q \cos(\theta), \quad (8a)$$

$$\kappa = \frac{\Delta Q}{\Delta \theta} \cos(\theta) + Q \sin(\theta)$$

$$+\frac{\Delta \theta}{6} (3Q + \Delta Q) \cos(\theta) + O(\Delta \theta)^3$$

$$\approx \frac{dQ}{d\theta} \cos(\theta) + Q \sin(\theta). \quad (8b)$$

Clearly we are free to choose a value of $\theta$ that simplifies the implementation of our system. If we choose $\theta = \pi/2$, which corresponds to an optical FT, then $\kappa = Q$ and $\xi = -(dQ/d\theta)$.

In conclusion, it has been shown that, by optically generating FRT planes of suitable order within a speckle photographic system, one can estimate both the tilting and the translation of the surface. The method requires the capture of four speckle images, two in one fractional domain and two in a second, i.e., $I_\theta(q_1;t_1)$, $I_{\theta+\Delta \theta}(q_2;t_2)$, $I_\theta(q_3;t_3)$, and $I_{\theta+\Delta \theta}(q_2';t_4)$, where for example the time sequence may be of the form $t_1 < t_2 \ll t_3 < t_4$. No discussion of possible techniques to implement a variable-order FRT has been presented here. However, clearly a practical system would require access to an accurate, fast electronically controlled method of FRT order variation. Furthermore, no discussion of speckle size or decorrelation or of the effect of the optics used on the operation of the system, e.g., noise introduction by the optical FRT itself, has been presented. These parameters will be critically important in determining the capabilities of any such system.

We believe that the geometrical method presented here provides a new way to describe and analyze optical metrology systems. Furthermore, it provides physical insights that have allowed us to propose new metrology systems. Initial experimental results have already been presented in the literature, and the practicality of these systems is currently being examined.

The authors acknowledge the support of Enterprise Ireland through the Research Innovation Fund. J. T. Sheridan’s e-mail address is john.sheridan@ucd.ie.

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